## Notice of References Cited Application/Control No. 10/813,410 Examiner Yogesh C. Garg Applicant(s)/Patent Under Reexamination CHANG ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0035450 A1	03-2002	Thackston, James D.	703/1
*	В	US-2003/0069824 A1	04-2003	Menninger, Anthony Frank	705/37
*	С	US-2003/0014326 A1	01-2003	Ben-Meir et al.	705/26
*	D	US-2003/0074301 A1	04-2003	Solomon, Neal	705/37
*	Ε	US-2002/0042769 A1	04-2002	Gujral et al.	705/37
*	F	US-7,146,331	12-2006	Young, Erik P.	705/26
	G	US-			
	H	US-			
	-	US-			
	J	US-			
	Κ	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0				•	
	P					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	×	

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